

HM8118

LCR-Bridge

Technical Data

HAMEG[®]
Instruments

A Rohde & Schwarz Company



Key facts

- Basic Accuracy 0.05 %
- Measurement Functions L, C, R, |Z|, X, |Y|, G, B, D, Q, Θ, Δ, M, N
- Test Frequencies 20 Hz...200 kHz
- Up to 12 Measurements per Second
- Parallel and Serial Mode
- Binning Interface HO118 (optional) for automatic Sorting of Components
- Internal programmable Voltage and Current Bias
- Transformer Parameter Measurement
- External Capacitor Bias up to 40 V
- Kelvin Cable and 4-Terminal SMD Test Adapter included
- Galvanically isolated USB/RS-232 Dual-Interface, optional IEEE-488 (GPIB)

Test & Measurement

Technical Data

PD 5210.8689.32 - 02.00

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200 kHz LCR-Bridge HM8118

All data valid at 23°C after 30 minutes warm-up.

Conditions

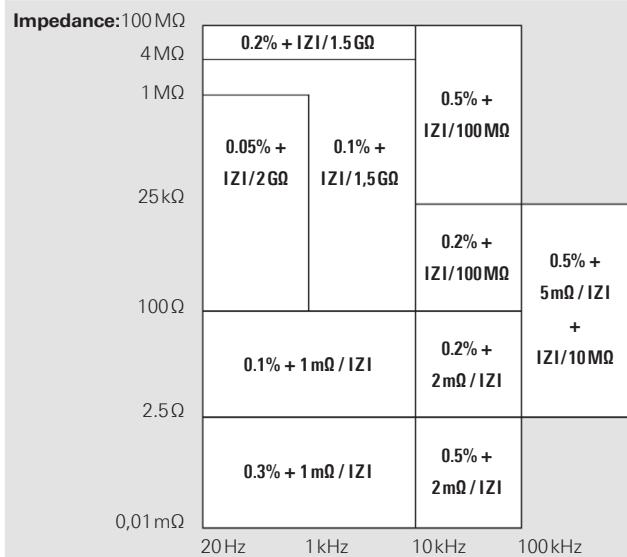
Test signal voltage	1V
Open and short corrections performed	
Measurement time	SLOW

Display

Measurement modes	Auto, L-Q, L-R, C-D, C-R, R-Q, Z-Θ, Y-Θ, R-X, G-B, N-Θ, M
Equivalent circuits	auto, series or parallel
Parameters displayed	Value, deviation or % deviation
Averaging	2 to 99 measurements

Genauigkeit

Primary parameters	Basic accuracy (Test voltage: 1.0V, measurement SLOW/MEDIUM, autoranging mode, constant voltage OFF, bias off). For FAST mode double the basic accuracy values
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Secondary parameters

Basic accuracy D, Q	±0,0001 if f = 1 kHz
Phase angle	±0,005° if f = 1 kHz

Ranges

Z , R, X	0,01 mΩ to 100 MΩ
Y , G, B	10nS to 1.000S
C	0,01 pF to 100mF
L	10nH to 100kH
D	0,0001 to 9,9999
Q	0,1 to 9.999,9
Θ	-180 to +180°
Δ	-999,99 to 999,99%
M	1µH to 100H
N	0,95 to 500

Measurement conditions and functions

Test frequency	20Hz to 200kHz (69 steps)
Frequency accuracy	±100 ppm
AC test signal level	50mVrms to 1.5Vrms
Resolution	10mVrms

Drive level accuracy	±(5% + 5mV)
Internal bias voltage	0 to +5,00VDC
Resolution	10mV
External bias voltage	0 to +40Vdc (fused 0.5 A)
Internal bias current	0 to +200mA
Resolution	1mA
Range selection	Auto and Hold
Trigger	Continuous, manual or external via interface, binning interface or trigger input
Trigger delay time	0 to 999ms in 1 ms steps
Measurement time (f ≥1 kHz)	
FAST	70ms
MEDIUM	125ms
SLOW	0,7s
Miscellaneous	
Test signal level monitor	Voltage, current
Error correction	Open, short, load
Save/Recall	9 instrument settings
Front-end protection	$V_{max} < \sqrt{2/C}$ @ $V_{max} < 200V$, C in Farads (1 Joule of stored energy)
Low potential and low current guarding	Ground, driven guard or auto (fused)
Constant voltage mode (25Ω source)	
Temperature effects R, L or C	±5ppm/°C
Interface	Dual interface USB/RS-232 (HO820), IEEE-488 (GPIB) (optional)
Safety	Safety class I (EN61010-1)
Power supply	110 to 230V ±10%, 50 to 60Hz, CAT II
Power consumption	approx. 20W
Operating temperature	+5 to +40°C
Storage temperature	-20 to +70°C
Rel. humidity	5 to 80% (non condensing)
Dimensions (W x H x D)	285 x 75 x 365mm
Weight	approx. 4kg

Accessories supplied: Line cord, operating manual, HZ184 4-terminal kelvin test cable and HZ188 4-terminal SMD component test fixture, CD

Recommended accessories:

HO118	Binning interface
HO880	Interface IEEE-488 (GPIB), galvanically isolated
HZ13	Interface cable (USB) 1.8m
HZ14	Interface cable (serial) 1:1
HZ33	Test cable 50Ω, BNC/BNC, 0.5m
HZ34	Test cable 50Ω, BNC/BNC, 1.0m
HZ42	19" rackmount kit 2RU
HZ72	GPIB-cable 2m
HZ181	4-terminal test fixture including shorting plate
HZ186	4-terminal transformer test cable